## Reconstruction

#### Reconstruction

• Given an image, can we reconstruct the 3D world that created the image?



## Why is reconstruction hard?

Perspective projection

• 
$$x = \frac{fX}{Z} + p_x$$
,  $y = \frac{fY}{Z} + p_y$ 

- Simple case: f = 1,  $p_x = p_y = 0$ •  $x = \frac{x}{z}$ •  $y = \frac{Y}{z}$
- (X, Y, Z) and  $(\lambda X, \lambda Y, \lambda Z)$  project to the same point!
  - "Ill-posed problem"

### Why is reconstruction hard?



• Multiple images can give a clue about 3D structure



• Parallax: nearby objects move more than far away objects





- Step 1: Need to find *correspondences* between pixels in image 1 and image 2
- Step 2: Use correspondences to locate point in 3D



## Reconstruction from correspondence

• Given known cameras, correspondence gives the location of 3D point (*Triangulation*)



## Reconstruction from correspondence

• Given a 3D point, correspondence gives relationship between cameras (*Pose estimation / camera calibration*)



## Next few classes

- How do we find correspondences?
- How do we use correspondences to reconstruct 3D?

#### Other applications of correspondence

- Image alignment
- Motion tracking
- Robot navigation







## Easy correspondence



by <u>Diva Sian</u>



by swashford

#### Harder case



by <u>Diva Sian</u>

by <u>scgbt</u>

## Harder still?



## Answer below (look for tiny colored squares...)



NASA Mars Rover images with SIFT feature matches

## Sparse vs dense correspondence

- Sparse correspondence: produce a few, high confidence matches
  - Good enough for estimating pose or relationship between cameras
  - Easier
- Dense correspondence: try to match every pixel
  - Needed if we want 3D location of every pixel





## A general pipeline for correspondence

- **1. Feature detection:** If sparse correspondences are enough, *choose points for which we will search for correspondences (feature points)*
- **2. Feature description:** For each point (or every pixel if dense correspondence), describe point using a *feature descriptor*
- **3. Feature matching:** Find best matching descriptors across two images (*feature matching*)
- 4. Use feature matches to perform downstream task, e.g., pose estimation



## Characteristics of good feature points



- Repeatability / invariance
  - The same feature point can be found in several images despite geometric and photometric transformations
- Saliency / distinctiveness
  - Each feature point is distinctive
  - Fewer "false" matches

## Goal: repeatability

• We want to detect (at least some of) the same points in both images.



#### No chance to find true matches!

• Yet we have to be able to run the detection procedure *independently* per image.

## Goal: distinctiveness

- The feature point should be distinctive enough that it is easy to match
  - Should *at least* be distinctive from other patches nearby



• A single pixel by itself is not distinctive



- Individual pixels are ambiguous
- Idea: Look at whole patches!





- Individual pixels are ambiguous
- Idea: Look at whole patches!





Matching patch centers

- Patches can be ambiguous too!
- What patches are distinctive?





- Corners are distinctive!
- How do we define/find corners?



## Corner detection

• Main idea: Translating window should cause large differences in patch appearance



## **Corner Detection: Basic Idea**

- We should easily recognize the point by looking through a small window
- Shifting a window in *any direction* should give a *large change* in intensity





along the edge direction

"corner": significant change in all directions

Source: A. Efros

## Corner detection the math

- Consider shifting the window W by (u,v)
  - how do the pixels in W change?
- Write pixels in window as a vector:



$$\phi_0 = [I(0,0), I(0,1), \dots, I(n,n)]$$
  
$$\phi_1 = [I(0+u, 0+v), I(0+u, 1+v), \dots, I(n+u, n+v)]$$

$$E(u,v) = \|\phi_0 - \phi_1\|_2^2$$

## Corner detection: the math

Consider shifting the window W by (u, v)

- how do the pixels in W change?
- compare each pixel before and after by summing up the squared differences (SSD)
- this defines an SSD "error" E(u,v):
   E(u,v)

$$= \sum_{(x,y)\in W} [I(x+u,y+v) - I(x,y)]^2$$

• We want E(u,v) to be as high as possible for all u, v!



#### Small motion assumption

Taylor Series expansion of *I*:

$$I(x+u, y+v) = I(x, y) + \frac{\partial I}{\partial x}u + \frac{\partial I}{\partial y}v + higher order terms$$

If the motion (u,v) is small, then first order approximation is good

$$I(x + u, y + v) \approx I(x, y) + \frac{\partial I}{\partial x}u + \frac{\partial I}{\partial y}v$$
$$\approx I(x, y) + [I_x \ I_y] \begin{bmatrix} u \\ v \end{bmatrix}$$
shorthand:  $I_x = \frac{\partial I}{\partial x}$ 

Plugging this into the formula on the previous slide...

#### Corner detection: the math

Consider shifting the window W by (u,v)

• define an SSD "error" *E(u,v)*:



$$E(u, v) = \sum_{\substack{(x,y) \in W \\ (x,y) \in W}} [I(x+u, y+v) - I(x,y)]^2$$
  
$$\approx \sum_{\substack{(x,y) \in W \\ (x,y) \in W}} [I(x,y) + I_x u + I_y v - I(x,y)]^2$$

## Corner detection: the math

Consider shifting the window W by (u, v)

• define an "error" *E(u,v)*:



$$E(u,v) \approx \sum_{\substack{(x,y) \in W}} [I_x u + I_y v]^2$$
$$\approx Au^2 + 2Buv + Cv^2$$
$$A = \sum_{\substack{(x,y) \in W}} I_x^2 \quad B = \sum_{\substack{(x,y) \in W}} I_x I_y \quad C = \sum_{\substack{(x,y) \in W}} I_y^2$$

• Thus, E(u,v) is locally approximated as a quadratic error function

## A more general formulation

- Maybe all pixels in the patch are not equally important
- Consider a "window function" w(x, y) that acts as weights

• 
$$E(u, v) = \sum_{(x,y) \in W} w(x, y) [I(x + u, y + v) - I(x, y)]^2$$

- Case till now:
  - w(x,y) = 1 inside the window, 0 otherwise

## Using a window function

• Change in appearance of window w(x,y) for the shift [u,v]:



Redoing the derivation using a window function

$$E(u, v) = \sum_{x,y \in W} w(x, y) [I(x + u, y + v) - I(x, y)]^{2}$$
  

$$\approx \sum_{x,y \in W} w(x, y) [I(x, y) + uI_{x}(x, y) + vI_{y}(x, y) - I(x, y)]^{2}$$
  

$$= \sum_{x,y \in W} w(x, y) [uI_{x}(x, y) + vI_{y}(x, y)]^{2}$$
  

$$= \sum_{x,y \in W} w(x, y) [u^{2}I_{x}(x, y)^{2} + v^{2}I_{y}(x, y)^{2} + 2uvI_{x}(x, y)I_{y}(x, y)]$$

# Redoing the derivation using a window function

•

$$E(u, v) \approx \sum_{\substack{x, y \in W \\ x, y$$



## The second moment matrix $E(u,v) \approx \begin{bmatrix} u & v \end{bmatrix} \begin{bmatrix} A & B \\ B & C \end{bmatrix} \begin{bmatrix} u \\ v \end{bmatrix}$ M $M = \sum_{x,y \in W} w(x,y) \begin{bmatrix} I_x(x,y)^2 & I_x(x,y)I_y(x,y) \\ I_x(x,y)I_y(x,y) & I_y(x,y)^2 \end{bmatrix}$ Second moment matrix Recall that we want E(u,v) to be as large as possible for all u,v

What does this mean in terms of M?

$$E(u, v) \approx \begin{bmatrix} u & v \end{bmatrix} \begin{bmatrix} A & B \\ B & C \end{bmatrix} \begin{bmatrix} u \\ v \end{bmatrix}$$

$$A = \sum_{(x,y)\in W} I_x^2$$

$$B = \sum_{(x,y)\in W} I_x I_y$$

$$C = \sum_{(x,y)\in W} I_y^2$$
Flat patch:  $I_x = 0$ 

$$I_y = 0$$

B

$$\begin{split} E(u,v) &\approx \begin{bmatrix} u & v \end{bmatrix} \begin{bmatrix} A & B \\ B & C \end{bmatrix} \begin{bmatrix} u \\ v \end{bmatrix} \\ A &= \sum_{(x,y) \in W} I_x^2 & \mathbf{M} \\ B &= \sum_{(x,y) \in W} I_x I_y \\ C &= \sum_{(x,y) \in W} I_y^2 & \mathbf{V} \\ Vertical edge: I_y &= 0 \\ E(0,v) &= 0 \quad \forall v \end{split}$$

$$E(u,v) \approx \begin{bmatrix} u & v \end{bmatrix} \begin{bmatrix} A & B \\ B & C \end{bmatrix} \begin{bmatrix} u \\ v \end{bmatrix}$$



## What about edges in arbitrary orientation?



$$E(u,v) \approx \begin{bmatrix} u & v \end{bmatrix} M \begin{bmatrix} u \\ v \end{bmatrix}$$

$$M\left[\begin{array}{c} u\\v\end{array}\right] = \left[\begin{array}{c} 0\\0\end{array}\right] \Leftrightarrow E(u,v) = 0$$

Solutions to Mx = 0 are directions for which E is 0: window can slide in this direction without changing appearance

$$E(u,v) \approx \begin{bmatrix} u & v \end{bmatrix} M \begin{bmatrix} u \\ v \end{bmatrix}$$

Solutions to Mx = 0 are directions for which E is 0: window can slide in this direction without changing appearance

For corners, we want no such directions to exist







## Eigenvalues and eigenvectors of M

- $Mx = 0 \Rightarrow Mx = \lambda x$ : x is an eigenvector of M with eigenvalue 0
- M is 2 x 2, so it has 2 eigenvalues  $(\lambda_{max}, \lambda_{min})$  with eigenvectors  $(x_{max}, x_{min})$
- $E(x_{max}) = x_{max}^T M x_{max} = \lambda_{max} ||x_{max}||^2 = \lambda_{max}$ (eigenvectors have unit norm)
- $E(x_{min}) = x_{min}^T M x_{min} = \lambda_{min} ||x_{min}||^2 = \lambda_{min}$

## Eigenvalues and eigenvectors of M

Eigenvalues and eigenvectors of M

- Define shift directions with the smallest and largest change in error
- $x_{max}$  = direction of largest increase in *E*
- $\lambda_{max}$  = amount of increase in direction  $x_{max}$
- $x_{min}$  = direction of smallest increase in *E*
- $\lambda_{min}$  = amount of increase in direction  $x_{min}$

## Interpreting the eigenvalues

